



IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE

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Patent Application

Inventor(s): R. E. Myer ✓ Case: 72
Serial No.: 09/656,933 ✓ Group Art Unit: 2858
Filing Date: September 7, 2000 ✓ Examiner: J. Nguyen ✓
Title: IMPROVED RF TEST PROBE ✓

THE COMMISSIONER OF PATENTS AND TRADEMARKS
WASHINGTON, D.C. 20231

SIR:

AMENDMENT

In response to the Examiner Nguyen's Office Action, please enter the following response.

IN THE CLAIMS

1. (Amended) An RF probe, comprising:

a conductive return;

a insulator having a contact surface;

a probe conductor adjacent to the insulator; and

a termination electrically positioned between the conductive return and the probe conductor, wherein the probe conductor is equidistant with the insulator along the contact surface.

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